

Solid State Devices, Inc.

14701 Firestone Blvd * La Mirada, Ca 90638 Phone: (562) 404-4474 * Fax: (562) 404-1773 ssdi@ssdi-power.com * www.ssdi-power.com

Designer's Data Sheet

Part Number/Ordering Information 1/

SGF48N20

^L Screening^{2/}

__ = Not Screened TX = TX Level TXV = TXV Level S = S Level

Lead Bend Options

(TO-254 only)

__ = Straight Leads UB = Up Bend DB = Down Bend

Package

M = TO-254 S1= SMD1

SGF48N20M and SGF48N20S1

40 AMP
GaN POWER FET
Enhancement Mode
200 VOLTS, 14 – 16 mΩ

FEATURES:

- 4th Generation Gallium Nitride Technology
- Exceptionally Low RDS(ON)
- · Low Q_G Simplifies Gate Drive Circuit
- · Very Fast Switching for High-Freq. Applications
- Low Thermal Resistance Hermetically Sealed Packages -Available in Chip-Scale Package (SMG.3-1)
- TX, TXV, and S-Level Screening Available²

APPLICATIONS:

- High Efficiency DC-DC/PoL Converters
- Motor Controller
- Robotics/Automation
- · Military and Aerospace

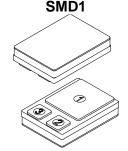
BENEFITS:

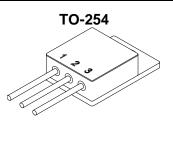
- GaN Transistor offers superior advantages over Si based MOSFET: Zero QRR, low gate charge, low RDS(ON), fast switching speed and low temperature coefficient
- · Benefits circuit designer through higher efficiency, lower cross-over losses and On-state losses
- Eliminates the need to add free-wheeling diode

Maximum Ratings ^{3/}	Symbol	Value	Units
Continuous Drain - Source Voltage	V _{DSS}	200	V
Gate – Source Voltage	$V_{\sf GS}$	+6 -4	v
Continuous Drain Current	I _{D1}	40	Α
Pulsed Drain Current (Top / Pwidth limited)	I _{D2}	200	Α
Total Power Dissipation	P _D	25	W
Operating & Storage Temperature	T _{OP} & T _{STG}	-55 to +150	°C
Thermal Resistance (Junction to Case)	R _{eJC}	5	°C/W

NOTES:

- 1/ For ordering information, price, operating curves, and availabilitycontact factory.
- 2/ Screening based on MIL-PRF-19500. Screening flows available on request.
- 3/ Unless otherwise specified, all electrical characteristics @ 25°C.
- 4/ Pulse Test, P_W = 300 μs, D.C. = 2%.
- 5/2 Attach device with low temperature solder such as Sn63 with peak reflow temperature of 215°C and maximum dwell time of 30 sec.





NOTE: All specifications are subject to change without notification. SCD's for these devices should be reviewed by SSDI prior to release.

DATA SHEET #: FT0072B

DOCX

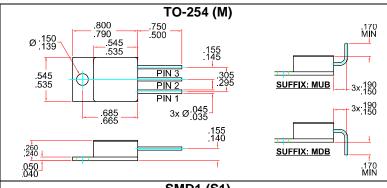


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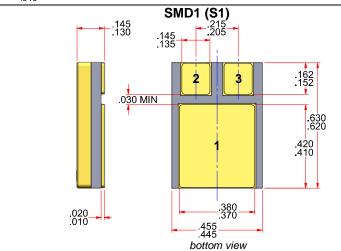
SGF48N20M and SGF48N20S1

Electrical Characteristics ^{3/}		Symbol	Min	Тур	Max	Unit
Drain to Source Breakdown Voltage Vo	$_{GS} = 0 \text{ V}, I_{D} = 0.6 \text{ mA}$	BV _{DSS}	200	-	-	V
Gate to Source Leakage	V _{GS} = +5 V V _{GS} = -4 V	I _{GSS}	-	1 0.1	7 0.4	mA
Zero Gate Voltage Drain Current V _D	_S = 160 V, V _{GS} = 0 V	I _{DSS}	-	0.1	0.4	mA
Gate Threshold Voltage	$V_{DS} = V_{GS}$, $I_D = 7 \text{ mA}$	V _{GS(TH)}	0.8	1.4	2.5	V
Drain to Source On State Resistance V _{GS} = 5 V, I _D = 20 A	SMD1 TO-254	R _{DS(ON)}	-	11 13	14 16	mΩ
Source to Drain Forward Voltage ^{4/}	$I_F = 0.5 A$, $V_{GS} = 0 V$	V_{SD}	-	1.8	-	٧
Total Gate Charge V _{GS} = 5 V, V _G	DS = 100 V, ID = 20 A	Q _G	-	9	11	nC
Gate to Source Charge Gate to Drain Charge Gate Threshold Charge	V _{DS} = 100 V I _D = 20 A	$oldsymbol{Q}_{GS} \ oldsymbol{Q}_{GD} \ oldsymbol{Q}_{GTH}$		3 1.8 2.2	- - -	nC
Input Capacitance Output Capacitance Reverse Transfer Capacitance	$\begin{aligned} V_{GS} &= 0 \text{ V} \\ V_{DS} &= 100 \text{ V} \\ f &= 1 \text{ MHz} \end{aligned}$	C _{ISS} C _{OSS} C _{RSS}		950 450 2.3	1140 680 -	pF
Output Charge Vo	ss = 0 V, V _{DS} = 100 V	Qoss	-	75	113	nC
Source to Drain Recovery Charge		\mathbf{Q}_{RR}	-	0	-	μC
Gate Resistance		R _G	-	0.5	-	Ω



PIN ASSIGNMENT					
	SMD1	TO-254			
Source	1	2			
Drain	3	1			
Gate	2	3			
Substrate	*	*			

^{*}Substrate internally tied to Source



AVAILABLE PART NUMBERS:

SMD1: SGF48N20S1

TO-254: SGF48N20M, SGF48N20MDB,

SGF48N20MUB

Dimensions in inches